Issue Classification

Application/Control No.	Applicant(s)/Patent Under Reexamination
10033210	SHIMIZU, SEIYA
Examiner	**Art Unit**
RICHARD M BEMBEN	2622

ORIGINAL

CLASS	SUBCLASS
725	105

CROSS REFERENCE(S)

CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
348	207.1	207.99	211.1	211.3	

INTERNATIONAL CLASSIFICATION

CLAIMED	NON-CLAIMED
H 0 4 N 7 / 173 (2006.01.01)	
H 0 4 N 5 / 225 (2006.01.01)	
H 0 4 N 9 / 04 (2006.01.01)	
H 0 4 N 5 / 232 (2006.01.01)	

/RICHARD M BEMBEN/ 3/17/08 (Assistant Examiner) (Date)		**Total Claims Allowed:** 5
/Lin Ye/ 3/17/08 (Primary Examiner) (Date)	O.G. Print Claim(s) 1	O.G. Print Figure 3